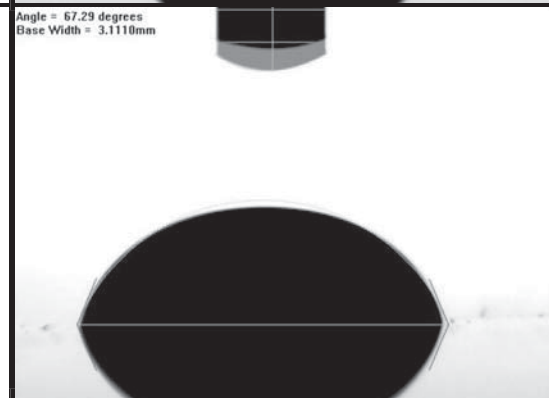
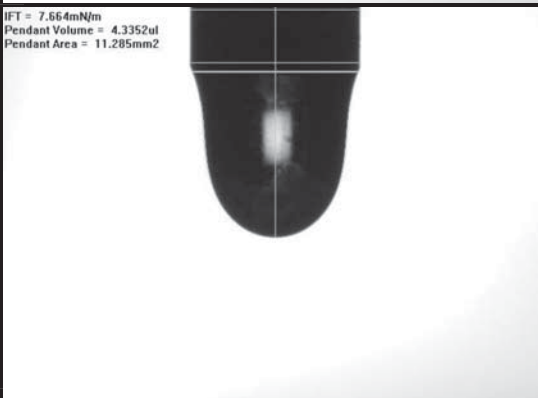
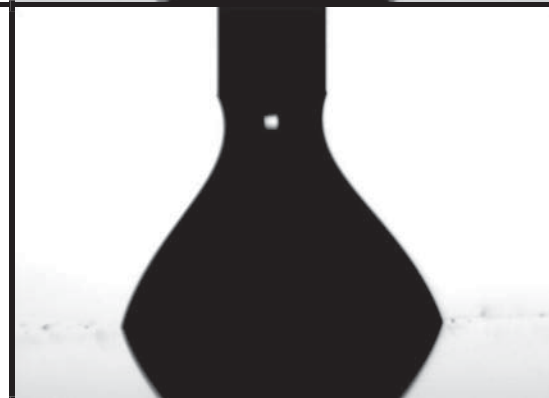
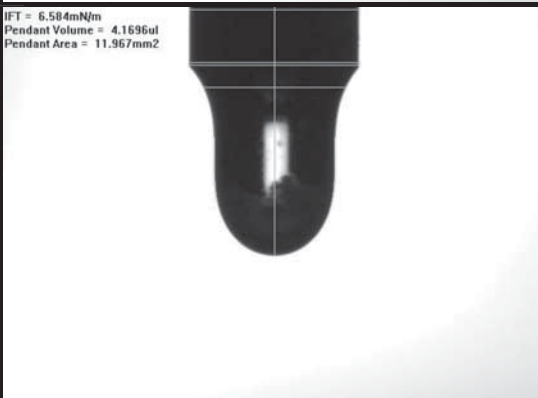
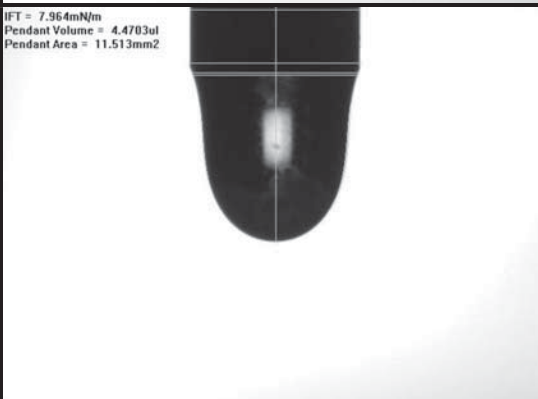
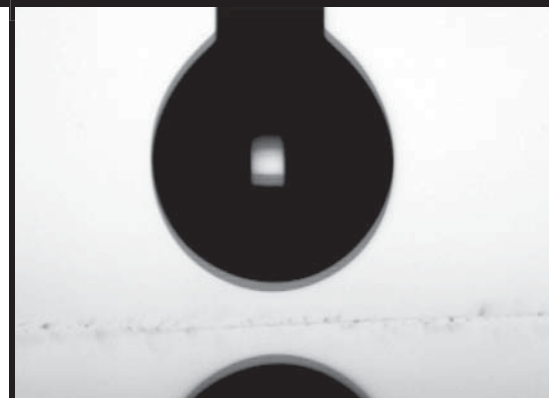
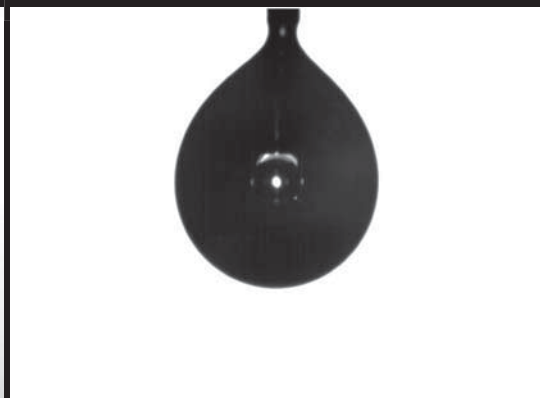
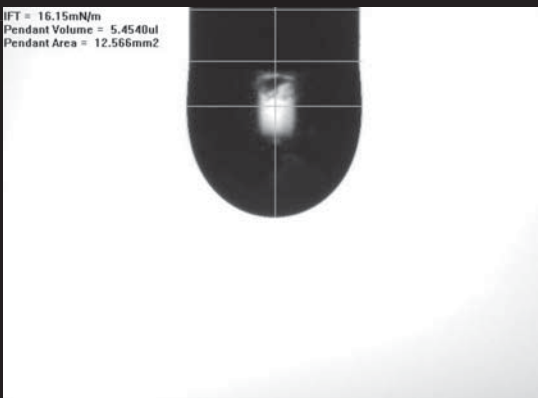


First Ten Ångstroms™

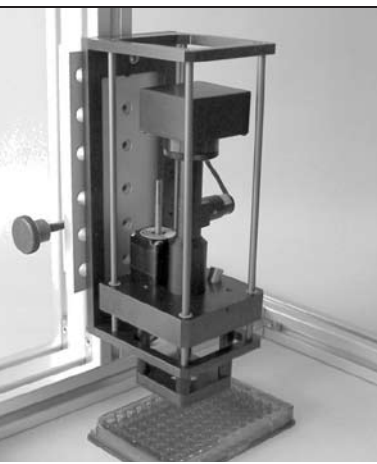
Dilational Stress to Low γ_{LV} (6 mN/m)

Drop Detachment at 250fps

Automated Touch-off



Surface Science Instruments with Real Vision™
Product Line



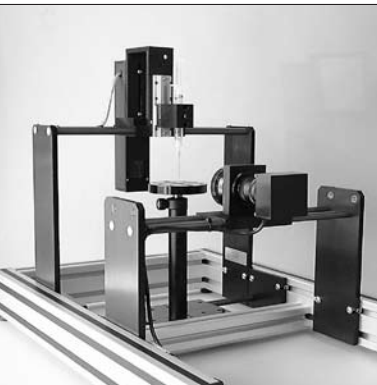
FTA1000 A Class

Special Purpose Dispense and Measurement Heads

- compact, modular, self-contained instruments
- mix-and-match controller, pumps, and heads
- heads can be located remotely on robotics
- provide contact angles and/or precision dispense
- all use small microscopes and cameras to verify dispense

- precision dispense of high-value picoliter and nanoliter drops
- jetting of heated polymers and solders
- top view contact angles for wells and low-angle surfaces
- classic side view contact angles

- OEM friendly (incorporate into your system)
- self-contained microprocessor: no host computer required
- built-in LCD and keypad
- supports local VGA, touchscreen, keyboard, mouse
- browser interface over Ethernet LAN or Internet



FTA1000 B Class

Economical Drop Shape Instruments

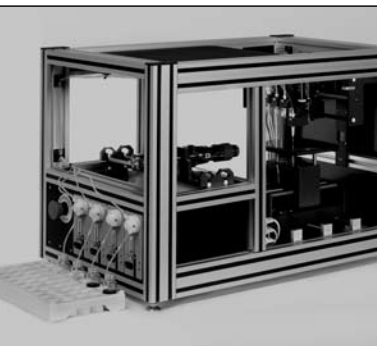
- expandable, upgradeable instruments
- contact angle and surface tension measurements

- user-swappable modules for entire electronics chain
- plug and play determination of options present
- excellent for QA and factory floor use
- some systems can be powered by laptop

- To design your instrument:
 - 1 choose stage and/or chamber
 - 2 choose camera + microscope + backlight combination
 - 3 choose dispense pump + tip Z control

- 36 page catalog available to explain all options, or
- let your distributor or FTA recommend a configuration
- pre-configured *student* edition in stock for immediate delivery

- Vista® compatible when Firewire camera chosen
- can use most FTA200 stages and chambers
- instrument tilt stage available



FTA1000 C Class


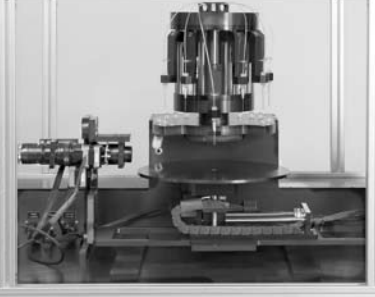
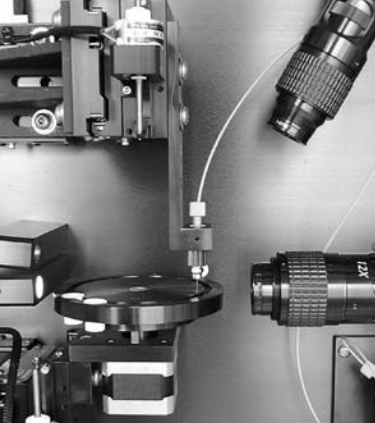

General Purpose Laboratory Drop Shape Instruments

- top-of-the-line general purpose laboratory instrument
- very wide range of modules available
- all modules user-installable
- variety of additional stages and chambers planned for future

- To design your instrument:
 - 1 choose stage and/or chamber
 - 2 choose camera + microscope + backlight combination
 - 3 choose dispense pump + tip Z control
 - steps 1-3 just like a B frame...*
 - 4 optionally add an autosampler
 - 5 optionally add a lookdown camera for locating drop on sample

- 1 and 4 pump options
- heated syringes possible

- all the flexibility of the B frame and more
- designed to be run by automation *one-click* scripts
- autosampler can support tip changer
- fixed mag, detented mag, and autozoom microscope options
- can interface to external hosts for robotic sample handler control

DCA-100	<ul style="list-style-type: none"> <input type="checkbox"/> economical force balance tensiometer <input type="checkbox"/> meets ASTM and DIN measurement standards 	
Contact Angle Tensiometer	<ul style="list-style-type: none"> <input type="checkbox"/> choice of 100µg or 1µg sensitivities <input type="checkbox"/> 100µg is robust and satisfactory for ring and plate IFT <input type="checkbox"/> 1µg provides sensitivity for 10µm fiber contact angles <input type="checkbox"/> advancing / receding contact angles by Wilhelmy immersion <input type="checkbox"/> calculates surface energies from contact angles <input type="checkbox"/> surface and interfacial tensions: liquid-vapor or liquid-liquid <input type="checkbox"/> ring or plate methods <input type="checkbox"/> critical micelle determination <input type="checkbox"/> temperature probe for liquid <input type="checkbox"/> density measurement <input type="checkbox"/> disposable paper plates for liquid-vapor surface tension <input type="checkbox"/> rod method for liquid-vapor surface tension 	
FTA2000	<ul style="list-style-type: none"> <input type="checkbox"/> 300mm wafer capable platter <input type="checkbox"/> can handle smaller wafers <input type="checkbox"/> can handle rectangular samples that fit within 300mm circle 	
Wafer Analyzer	<ul style="list-style-type: none"> <input type="checkbox"/> contact angle and surface tension analysis <input type="checkbox"/> platter and camera tilt through 90° for receding angle analysis <input type="checkbox"/> 6 tip, 17 liquid vial, autosampler <input type="checkbox"/> tip changer option available <input type="checkbox"/> fully enclosed <input type="checkbox"/> clean room compatible <input type="checkbox"/> temperature stabilized to 40C <input type="checkbox"/> autofocus, autozoom microscope <input type="checkbox"/> adjustable lookdown angle <input type="checkbox"/> script programmable for unattended operation <input type="checkbox"/> macros to automate drop formation and baseline determination <input type="checkbox"/> host computer interface to coordinate sample loading <input type="checkbox"/> SECS interface available 	
FTA4000	<ul style="list-style-type: none"> <input type="checkbox"/> piezo-electric jetting for picoliter drops <input type="checkbox"/> jetted volumes down to 20 picoliters <input type="checkbox"/> can also form classical pendant drops up to µl volumes <input type="checkbox"/> automated touch-off for classical drops <input type="checkbox"/> dip-and-sip for low volume pump prime 	
Small Drop Contact Angle Analyzer	<ul style="list-style-type: none"> <input type="checkbox"/> two camera design: horizontal analytical and lookdown locator <input type="checkbox"/> zoom microscopes on both axes <input type="checkbox"/> all optics mount on single surface plate for stability <input type="checkbox"/> two halogen illuminators adjustable for best image contrast <input type="checkbox"/> enclosed cabinet for stability <input type="checkbox"/> X-Y-Z-θ automated specimen stage <input type="checkbox"/> special analysis software for rapid absorption work 	
Legacy Instruments	<p>The following instruments have been replaced by the FTA1000:</p> <p>FTA125, FTA135, FTA136, FTA137, FTA188, FTA200</p>	
	<p>If you need one of these units, say to match a setup at another facility, they can be obtained by special order. There will be a lead time and the price will reflect a custom order charge.</p>	

Useful Formulas

<p>Young's Equation Contact angle of liquid on surface Also, the force balance on a spherical sessile drop</p> $\gamma_{SV} - \gamma_{SL} = \gamma_{LV} \cos \theta$ <p> γ_{SV} = solid vapor IFT (aka <i>surface energy</i> of solid) γ_{SL} = solid liquid IFT (IFT = interfacial tension) γ_{LV} = liquid vapor IFT (aka <i>surface tension</i> of liquid) θ = contact angle of drop (angle in liquid at three-phase line)</p>	<p>Laplace Pressure across Curved Surface</p> $\Delta P = \gamma_{LV} (1/R_1 + 1/R_2)$ <p> $\Delta P = \perp$ pressure differential across interface R_1, R_2 = principal radii of curvature of interface at \perp point for sphere, $R_1 = R_2$ = radius of sphere</p>
<p>Spherical Drop Geometry</p> $\theta = 2 \arctan(2h / d)$ <p> h = height of drop d = diameter of drop's wetted surface on solid θ = contact angle of drop</p>	<p>Laplace-Young Equation IFT of liquid-vapor (γ_{LV}) or liquid-liquid (γ_{LL}) interface</p> $mgh = \Delta P = \gamma_{LV} (1/R_1 + 1/R_2)$ <p> m = density differential across interface g = acceleration of gravity h = vertical position with drop, measured from apex</p>
<p>Force on Wilhelmy Plate</p> $F = L \gamma_{LV} \cos \theta$ <p> F = force on plate L = wetted perimeter length</p>	<p>Force - Mass (Weight) Relationship</p> $F = mg$ <p> F = force (in Newtons) measured by balance m = mass (in kilograms) g = acceleration of gravity, nominally 9.8m/s² e.g. 1 gram mass → 9.8 milli Newton force</p>
<p>Basic Statistics</p> $\mu = \sum x_i / n$ $\sigma = \sqrt{\{ 1/(n-1) \sum (x_i - \mu)^2 \}}$ $COV = \sigma / \mu$ <p> n = number of items i = index of item (for summations) x_i = value of ith item μ = mean value (aka <i>average</i>) of set σ = standard deviation of set COV = coefficient of variance</p>	<p>Hook's Law and Dilational Stress</p> $\tau = G \gamma$ $\tau(t) = G(t) \gamma(t)$ $G' = \tau_0 \cos(\phi) / \gamma_0$ $G'' = \tau_0 \sin(\phi) / \gamma_0$ $\eta' = G'' / \omega$ $\eta'' = G' / \omega$ <p> τ = stress, or force per unit area $\tau(t)$ = time varying stress, typically $\tau_0 \sin(\omega t)$ G, G(t) = elastic modulus γ = strain, relative change in length (or shape) $\gamma(t)$ = time varying strain, typically $\gamma_0 \sin(\omega t + \phi)$ G' = in-phase <i>elastic</i> modulus G'' = out-of-phase <i>viscous</i> modulus η' = dynamic viscosity η'' = dynamic elasticity</p>
<p>Wetting Tension Characterizes solid surface by RHS of Young's equation:</p> $WT = \gamma_{LV} \cos \theta$ <p>Note this varies from $-\gamma_{LV}$ (at 180°) to $+\gamma_{LV}$ (at 0°)</p>	<p>Zisman's Critical Wetting Tension</p> <p>Critical Wetting Tension (CWT) is defined as intersection of IFT-cos θ plot line with cos 0° (IFT on X axis, cos θ on Y). IFT at this point is CWT. Experimentally it is found $CWT \approx \gamma_{SV}$</p>
<p>Girifalco-Good-Fowkes-Young Rule Uses the combining rule $\gamma_{SL} = (\sqrt{\gamma_{SV}} - \sqrt{\gamma_{LV}})^2$</p> $1 + \cos \theta = 2 \sqrt{(\gamma_{SV} / \gamma_{LV})} - \pi / \gamma_{LV}$ <p>π = spreading pressure (often ≈ 0)</p>	<p>Owens-Wendt Geometric Mean Mean</p> $(1 + \cos \theta) \gamma_{LV} = 2 \sqrt{(\gamma_{SV}^D \gamma_{LV}^D)} + 2 \sqrt{(\gamma_{SV}^P \gamma_{LV}^P)}$ <p>D superscript indicates dispersive and P polar component</p>
<p>Wu's Harmonic Mean Rule</p> $(1 + \cos \theta) \gamma_{LV} = 4 \{ \gamma_{SV}^D \gamma_{LV}^D / (\gamma_{SV}^D + \gamma_{LV}^D) + \gamma_{SV}^P \gamma_{LV}^P / (\gamma_{SV}^P + \gamma_{LV}^P) \}$	<p>Lewis Acid/Base Rule</p> $(1 + \cos \theta) \gamma_{LV} = 2 \sqrt{(\gamma_{SV}^D \gamma_{LV}^D)} + 2 \sqrt{(\gamma_{SV}^A \gamma_{LV}^B)} + 2 \sqrt{(\gamma_{SV}^B \gamma_{LV}^A)}$ <p>A superscript indicates acid and B base component</p>
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